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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10073314	02/13/2002	257	7	2814	<i>FAK-HANI</i>

**APPLICANTS: Hoshi Kenji, Nomura Hiroshi, Ishibashi Shigeru, Shi Yi-Yu;

FAK-HANI

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-162788 05/30/2001

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed ☐ yes ☐ no

35 USC 119 conditions met ☐ yes ☐ no

Verified and Acknowledged Examiners's initials

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TITLE : Semiconductor device and alignment sensing method for semiconductor device

U.S. DEPT. OF COMM. / PAT. & TM. PTO-436 (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Assistant Examiner	
ISSUE FEE		Total Clm No	
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		Sheet No	Fig. No
		Print Fig	
<input checked="" type="checkbox"/> TERMINAL DISCLAIMER		Primary Examiner	
		Application Examiner	
		PREPARED FOR ISSUE	
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